

Search Notes**Application/Control No.**

10/625,631

Examiner

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Applicant(s)/Patent under Reexamination

ITO ET AL.

Art Unit

2825

SEARCHED

Class	Subclass	Date	Examiner
716	11	3/16/2006	JSL
716	8	3/16/2006	JSL
716	9	3/16/2006	JSL
716	10	3/16/2006	JSL

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST [USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB]	3/16/2006	JSL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner